

Bill of Materials

Generic	Material List	Wire Size	DIE ATTACH EPOXY	MOLD COMPOUND	
				FROM	TO
AD5544	AD5544ACPZ-1-RL7 AD5544BCPZ-RL7	1.0 mil	ABLESTIK 8290	SUMITOMO G770	SUMITOMO G700
AD5628	AD5628ACPZ-1-RL7 AD5628ACPZ-2-RL7 AD5628BCPZ-2-RL7 AD5628BCPZ-2-U1				
AD5629R	AD5629RACPZ-2-RL7 AD5629RACPZ-3-RL7 AD5629RBCPZ-1-RL7 AD5629RBCPZ-2-RL7				
AD5668	AD5668ACPZ-2-RL7 AD5668ACPZ-3-RL7 AD5668BCPZ-1500RL7 AD5668BCPZ-1-RL7 AD5668BCPZ-2500RL7 AD5668BCPZ-2-RL7				
AD5669R	AD5669RACPZ-2-RL7 AD5669RACPZ-3-RL7 AD5669RBCPZ-1500R7 AD5669RBCPZ-1-RL7 AD5669RBCPZ-2500R7 AD5669RBCPZ-2-RL7				

Qualification Data for LFCSP Devices at Amkor Philippines

QUALIFICATION RESULTS 20-LFCSP

TEST	SPECIFICATION	SAMPLE SIZE (LOT/QTY)	RESULTS
High Temperature Storage (HTS)	JESD22-A103 150°C, 1000 hours	1 x 77	Pass
Temperature Cycle*	JES22-A104, -65°C to +150°C, 2 cycle per hour, 500 cycles	3 x 77	Pass
Biased HAST *	JESD22-A110, 130°C, 85% RH, 96hrs	3 x 77	Pass
Autoclave *	JESD22-A102, 121°C, 100% RH, 96hrs	3 x 77	Pass
Solder Heat Resistance (SHR)*	JEDEC/IPC J-STD-020	3 x 11	Pass
Electrostatic Discharge (ESD) Field Induced Charged Device Model (FICDM)	JESD22-C101, >500V	1 x 3	Pass

Qualification Data for LFCSP Devices at Amkor Philippines cont.

QUALIFICATION RESULTS 48-LFCSP			
TEST	SPECIFICATION	SAMPLE SIZE (LOT/QTY)	RESULTS
High Temperature Storage (HTS)	JESD22-A103 150°C, 1000 hours	1 x 45	Pass
Temperature Cycle*	JES22-A104, -65°C to +150°C, 2 cycle per hour, 500 cycles	3 x 45	Pass
Biased HAST *	JESD22-A110, 130°C, 85% RH, 96hrs	3 x 45	Pass
Autoclave *	JESD22-A102, 121°C, 100% RH, 96hrs	3 x 45	Pass
Solder Heat Resistance (SHR)*	JEDEC/IPC J-STD-020	3 x 11	Pass
Electrostatic Discharge (ESD) Field Induced Charged Device Model (FICDM)	JESD22-C101, >500V	1 x 3	Pass

*Preconditioned Per JEDEC/IPC J-STD-020

TEST PRODUCT QUALIFICATION REPORT

TITLE:

Test Transfer of AD5628 (LFCSP) from STATS
ChipPAC Malaysia (SCM) to STATS ChipPAC China
(SCC)

PCN NUMBER:

14_0005

REVISION:

A

DATE:

04 June 2014

PROJECT BACKGROUND

Test transfers are carried out to qualify STATS ChipPAC China (SCC) as an additional test site for ADI devices to support production, and where STATS ChipPAC Malaysia (SCM) factory will shut down in 2014.

SUMMARY

AD5628 LFCSP will be transferred from SCM to SCC.

There is no change to the form, fit, function, quality or reliability between platforms.

This report documents the successful completion of the product test transfer requirements of AD5628 LFCSP from SCM to SCC.

Test product qualification was performed according to Analog Devices Specification (ADI0012 / TST000137 / TST00095)

TEST AND PRODUCT INFORMATION

Device: AD5628
Package: LFCSP-4x4x0.75
Leads: 16
Tester Platform: MFLXMS
Handler: Delta Edge

Description and Test Results

Table 1 provides a description of the qualification tests conducted and corresponding test results for AD5628LFCSP. All the units have undergone electrical tests on both the sending and receiving sites on the same test platform. Any device that did not meet the electrical qualification requirements without further analysis and data to prove passing, the qualification would be considered failed.

Table 1. Test Product Transfer Qual Criteria

Generic	Package	Lot number	Lot Size	Sending Site	Receiving Site	Mean Shift =< 0.5sigma	Sigma Ratio =< 1.3
AD5628	4x4x0.75 LFCSP	2712737.1	100	SCM	SCC	Passed	Passed

The AD5628 was qualified by running a qualification lot with 100 units both in SCM and SCC. Data between sites were analyzed as summarized in Table 1.

A passing result was recorded when the yield from receiving site met or exceeded yield from sending site as summarized in Table 2. Succeeding lots with increased quantity will be closely monitored once the device has started production run at SCC.

Table 2. Test Product Transfer Qualification Lot Run

GENERIC	Package	Lot number	Lot Size	Test Site	Results
AD5628	4x4x0.75 LFCSP	2712737.1	100	SCC	Passed

No valid rejects were encountered during the said evaluation in both sending and receiving sites.

Rejects Verifications

5 valid rejects tested in SCM and SCC having the same result.

Table 3. Setup verification using Reject units

Unit #	SCM	SCC
1	Failed	Failed
2	Failed	Failed
3	Failed	Failed
4	Failed	Failed
5	Failed	Failed

Conclusion:

AD5628 LFCSP handler correlation data on both sites are correlated. Data are already approved by PE and CY, it is acceptable. AD5628 LFCSP device is now ready for transfer to SCC.

Approvals

TRB#9670
Test Product Engineer
Chute Yield Engineer

Supporting Documents

Technical Review Board: TRB#9670

Additional Information

Homepage: <http://www.analog.com/en/index.html>
Datasheet: <http://www.analog.com/en/analog-to-digital-converters/video-decoders/AD5628/products/product.html>
Customer Service: http://www.analog.com/en/content/technical_support_page/fca.html

TEST PRODUCT QUALIFICATION REPORT

TITLE:

Test Transfer of AD5629R (LFCSP) from STATS
ChipPAC Malaysia (SCM) to STATS ChipPAC China
(SCC)

PCN NUMBER:

14_0005

REVISION:

A

DATE:

04 June 2014

PROJECT BACKGROUND

Test transfers are carried out to qualify STATS ChipPAC China (SCC) as an additional test site for ADI devices to support production, and where STATS ChipPAC Malaysia (SCM) factory will shut down in 2014.

SUMMARY

AD5629R LFCSP will be transferred from SCM to SCC.

There is no change to the form, fit, function, quality or reliability between platforms.

This report documents the successful completion of the product test transfer requirements of AD5629R LFCSP from SCM to SCC.

Test product qualification was performed according to Analog Devices Specification (ADI0012 / TST000137 / TST00095)

TEST AND PRODUCT INFORMATION

Device: AD5629R
Package: LFCSP-4x4x0.75
Leads: 16
Tester Platform: MFLEXMS
Handler: Delta Edge

Description and Test Results

Table 1 provides a description of the qualification tests conducted and corresponding test results for AD5629R LFCSP. All the units have undergone electrical tests on both the sending and receiving sites on the same test platform. Any device that did not meet the electrical qualification requirements without further analysis and data to prove passing, the qualification would be considered failed.

Table 1. Test Product Transfer Qual Criteria

Generic	Package	Lot number	Lot Size	Sending Site	Receiving Site	Mean Shift =< 0.5sigma	Sigma Ratio =< 1.3
AD5629R	4x4x0.75 LFCSP	2772704.1	100	SCM	SCC	Passed	Passed

The AD5629R was qualified by running a qualification lot with 100 units both in SCM and SCC. Data between sites were analyzed as summarized in Table 1.

A passing result was recorded when the yield from receiving site met or exceeded yield from sending site as summarized in Table 2. Succeeding lots with increased quantity will be closely monitored once the device has started production run at SCC.

Table 2. Test Product Transfer Qualification Lot Run

GENERIC	Package	Lot number	Lot Size	Test Site	Results
AD5629R	4x4x0.75 LFCSP	2633592.1	100	SCC	Passed

No valid rejects were encountered during the said evaluation in both sending and receiving sites.

Rejects Verifications

5 valid rejects tested in SCM and SCC having the same result.

Table 3. Setup verification using Reject units

Unit #	SCM	SCC
1	Failed	Failed
2	Failed	Failed
3	Failed	Failed
4	Failed	Failed
5	Failed	Failed

Conclusion

AD5629R LFCSP handler correlation data on both sites are correlated. Data are already approved by PE and CY, it is acceptable. AD5629R LFCSP device is now ready for transfer to SCC.

Approvals

TRB#9670

Test Product Engineer

Chute Yield Engineer

Supporting Documents

Technical Review Board: TRB#9670

Additional Information

Homepage: <http://www.analog.com/en/index.html>

Datasheet: <http://www.analog.com/en/analog-to-digital-converters/video-decoders/AD5629R/products/product.html>

Customer Service: http://www.analog.com/en/content/technical_support_page/fca.html

TEST PRODUCT QUALIFICATION REPORT

TITLE:

Test Transfer of AD5668 (LFCSP) from STATS
ChipPAC Malaysia (SCM) to STATS ChipPAC China
(SCC)

PCN NUMBER:

14_0005

REVISION:

A

DATE:

04 June 2014

PROJECT BACKGROUND

Test transfers are carried out to qualify STATS ChipPAC China (SCC) as an additional test site for ADI devices to support production, and where STATS ChipPAC Malaysia (SCM) factory will shut down in 2014.

SUMMARY

AD5668 LFCSP will be transferred from SCM to SCC.

There is no change to the form, fit, function, quality or reliability between platforms.

This report documents the successful completion of the product test transfer requirements of AD5668 LFCSP from SCM to SCC.

Test product qualification was performed according to Analog Devices Specification (ADI0012 / TST000137 / TST00095)

TEST AND PRODUCT INFORMATION

Device: AD5668
Package: LFCSP-4x4x0.75
Leads: 16
Tester Platform: MFLXMS
Handler: Delta Edge

Description and Test Results

Table 1 provides a description of the qualification tests conducted and corresponding test results for AD5668LFCSP. All the units have undergone electrical tests on both the sending and receiving sites on the same test platform. Any device that did not meet the electrical qualification requirements without further analysis and data to prove passing, the qualification would be considered failed.

Table 1. Test Product Transfer Qual Criteria

Generic	Package	Lot number	Lot Size	Sending Site	Receiving Site	Mean Shift =< 0.5sigma	Sigma Ratio =< 1.3
AD5668	4x4x0.75 LFCSP	2657432.1	100	SCM	SCC	Passed	Passed

The AD5668 was qualified by running a qualification lot with 100 units both in SCM and SCC. Data between sites were analyzed as summarized in Table 1.

A passing result was recorded when the yield from receiving site met or exceeded yield from sending site as summarized in Table 2. Succeeding lots with increased quantity will be closely monitored once the device has started production run at SCC.

Table 2. Test Product Transfer Qualification Lot Run

GENERIC	Package	Lot number	Lot Size	Test Site	Results
AD5668	4x4x0.75 LFCSP	2657432.1	100	SCC	Passed

No valid rejects were encountered during the said evaluation in both sending and receiving sites.

Rejects Verifications

5 valid rejects tested in SCM and SCC having the same result.

Table 3. Setup verification using Reject units

Unit #	SCM	SCC
1	Failed	Failed
2	Failed	Failed
3	Failed	Failed
4	Failed	Failed
5	Failed	Failed

Conclusion:

AD5668 LFCSP handler correlation data on both sites are correlated. Data are already approved by PE and CY, it is acceptable. AD5668 LFCSP device is now ready for transfer to SCC.

Approvals

TRB#9972
 Test Product Engineer
 Chute Yield Engineer

Supporting Documents

Technical Review Board: TRB#9972

Additional Information

Homepage: <http://www.analog.com/en/index.html>
 Datasheet: <http://www.analog.com/en/analog-to-digital-converters/video-decoders/AD5668/products/product.html>
 Customer Service: http://www.analog.com/en/content/technical_support_page/fca.html

TEST PRODUCT QUALIFICATION REPORT

TITLE:

Test Transfer of AD5669R (LFCSP) from STATS
ChipPAC Malaysia (SCM) to STATS ChipPAC China
(SCC)

PCN NUMBER:

14_0005

REVISION:

A

DATE:

04 June 2014

PROJECT BACKGROUND

Test transfers are carried out to qualify STATS ChipPAC China (SCC) as an additional test site for ADI devices to support production, and where STATS ChipPAC Malaysia (SCM) factory will shut down in 2014.

SUMMARY

AD5669R LFCSP will be transferred from SCM to SCC.

There is no change to the form, fit, function, quality or reliability between platforms.

This report documents the successful completion of the product test transfer requirements of AD5669R LFCSP from SCM to SCC.

Test product qualification was performed according to Analog Devices Specification (ADI0012 / TST000137 / TST00095)

TEST AND PRODUCT INFORMATION

Device: AD5669R
Package: LFCSP-4x4x0.75
Leads: 16
Tester Platform: MFLXMS
Handler: Delta Edge

Description and Test Results

Table 1 provides a description of the qualification tests conducted and corresponding test results for AD5669RLFCSP. All the units have undergone electrical tests on both the sending and receiving sites on the same test platform. Any device that did not meet the electrical qualification requirements without further analysis and data to prove passing, the qualification would be considered failed.

Table 1. Test Product Transfer Qual Criteria

Generic	Package	Lot number	Lot Size	Sending Site	Receiving Site	Mean Shift =< 0.5sigma	Sigma Ratio =< 1.3
AD5669R	4x4x0.75 LFCSP	2754766.1	100	SCM	SCC	Passed	Passed

The AD5669R was qualified by running a qualification lot with 100 units both in SCM and SCC. Data between sites were analyzed as summarized in Table 1.

A passing result was recorded when the yield from receiving site met or exceeded yield from sending site as summarized in Table 2. Succeeding lots with increased quantity will be closely monitored once the device has started production run at SCC.

Table 2. Test Product Transfer Qualification Lot Run

GENERIC	Package	Lot number	Lot Size	Test Site	Results
AD5669R	4x4x0.75 LFCSP	2754766.1	100	SCC	Passed

No valid rejects were encountered during the said evaluation in both sending and receiving sites.

Rejects Verifications

5 valid rejects tested in SCM and SCC having the same result.

Table 3. Setup verification using Reject units

Unit #	SCM	SCC
1	Failed	Failed
2	Failed	Failed
3	Failed	Failed
4	Failed	Failed
5	Failed	Failed

Conclusion:

AD5669R LFCSP handler correlation data on both sites are correlated. Data are already approved by PE and CY, it is acceptable. AD5669R LFCSP device is now ready for transfer to SCC.

Approvals

TRB#9670
Test Product Engineer
Chute Yield Engineer

Supporting Documents

Technical Review Board: TRB#9670

Additional Information

Homepage: <http://www.analog.com/en/index.html>
Datasheet: <http://www.analog.com/en/analog-to-digital-converters/video-decoders/ad5669r/products/product.html>
Customer Service: http://www.analog.com/en/content/technical_support_page/fca.html